Magnetic thin films and multilayers



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Moor's Law:



Microprocessor Transistor Counts 1971-2011 & Moore's Law



22nm technology

SRAM cell size is $0.092 \ \mu m^2$



Koomey's Law

3 April 2014



IEEE TRANSACTIONS ON ELECTRON DEVICES, VOL. 54, NO. 5, MAY 2007

(0.18 μ m TMR/CMOS, V_{DD}=1.8V)

51µW

55nW

16µW

0.084nW

Dynamic

power

3 April 2014 power

New Physical Phenomena in magnetic multilayers:



Giant magnetoresistance:

Oscillatory inter-layer coupling + Spin dependent scattering



 $H_{\rm ex} = -J_{ij} \cdot S_i \cdot S_j$

Ruderman, Kittel, Kasuga, and Yoshida interaction:

spin polarization of the s and p electrons of the surrounding Medium by exchange interaction with d electrons of magnetic atoms

$$J_{ij(RKKY)}(R) \sim rac{\cos(2k_{
m F} \cdot R)}{(2k_{
m F} \cdot R)^3} \sim rac{1}{R^3}$$







 $MR ratio = (R_{AP} - R_{P}) / R_{P}$

Tunnel magnetoresistance:





Parallel (P) state Tunnel resistnce: R_P



Antiparallel (AP) state Tunnel resistnce: R_{AP}

MR ratio = $(R_{AP} - R_{P})/R_{P}$

Parallel stateAntiparallel state
$$J^{parallel} \propto D_1^{\uparrow} D_2^{\uparrow} + D_1^{\downarrow} D_2^{\downarrow}$$
 $J^{antiparallel} \propto D_1^{\uparrow} D_2^{\downarrow} + D_1^{\downarrow} D_2^{\uparrow}$ $P = \frac{D^{\uparrow}(E_F) - D^{\downarrow}(E_F)}{D^{\uparrow}(E_F) + D^{\downarrow}(E_F)}$ $TMR = \frac{\Delta R}{R_{AP}} = \frac{2 P_1 P_2}{1 + P_1 P_2}$ Jullière, Phys. Lett.
A54 225 (1975)

Fe/MgO(001)/Fe



- Theoretically predicted TMR ~1000
- Maximum experimentally observed value ~500

Imperfections at the interfaces are responsible for deterioration in TMR

Exchange spring magnets:







- 1

- 2

- 1

0

Н (Т)

1

2



Magnetic anisotropy

-magneto-crystalline
-stress induced
-surface/interface
- reduced symmetry
-surface roughness

Magneto-crystalline anisotropy:





Spin-orbit coupling



Shape anisotropy:



In general, magnetization and magnetic induction are not necessarily parallel



In thin films shape anisotropy dominates over magnetocrystalline anisotropy Stress induced anisotropy:



Magnetostriction

Intrinsic stresses:









$Fe_{0.88}N_{0.12}$ thin films:

Film thickness dependent properties



With increasing film thickness soft magnetic properties deteriorate

Strain measurement (XRD)



Surface anisotropy:



Broken symmetry at the surface / interface

$$K_{tot} = K_V + K_S / t$$







Au/Co/Au



Thickness dependence of anisotropy:



J. Fassbender et al., New J. Phys. 11 (2009) 125002

Exchange anisotropy:



exchange

Magnetism at surface and interfaces





Fe (001)

Enhanced magnetic moment at the surface